

**Appln No. 09/640,963**  
**Amdt date April 11, 2005**  
**Reply to Office action of January 10, 2005**

**REMARKS/ARGUMENTS**

Claims 1-45 remain pending in this application, of which claims 1-26, 43, and 44 stand allowed. Independent claims 27 and 34 have been amended. The amendments find full support in the original specification, claims, and drawings. No new matter has been added. In view of the above amendments and remarks that follow, reconsideration, reexamination, and an early indication of allowance of the remaining claims 27-42 and 45 are respectfully requested.

Claims 27, 31, 34-35, and 40-42 are rejected under 35 U.S.C. 103(a) as being unpatentable over Abe et al. (U.S. Patent No. 6,693,889). Claims 28-30 and 36-39 are rejected under 35 U.S.C. 103(a) as being unpatentable over Abe and further in view of Li (U.S. Patent No. 6,385,752). Applicant respectfully traverses these rejections.

Independent claim 27 has been amended to recite a "method of using puncture masks comprising: retrieving a compressed puncture mask from a semiconductor memory, the compressed puncture mask being generated according to a compression mechanism that compresses puncture mask data; decompressing the compressed puncture mask to generate the puncture mask data; and deleting particular bits from a data sequence according to the puncture mask data in the decompressed puncture mask." Nothing in Abe teaches or suggests this limitation. Although Abe discloses a reference matrix for generating various puncturing patterns, nothing in Abe teaches or suggests that such a reference matrix is "generated according to a compression mechanism that compresses puncture mask data" as is now required

**Appln No. 09/640,963**  
**Amdt date April 11, 2005**  
**Reply to Office action of January 10, 2005**

by claim 27. Furthermore, the act of generating the various puncturing patterns from the reference matrix which the Examiner contends reads upon the recited "decompressing" step does not "generate the puncture mask data" as is also now required by claim 27. Accordingly, claim 27 is now in condition for allowance.

Claim 34 has been amended to recite an "integrated circuit having a memory wherein the memory comprises a plurality of compressed puncture masks, each compressed puncture mask being generated according to a compression mechanism that compresses puncture mask data, the compressed puncture mask being retrieved from the memory and decompressed to generate the puncture mask data, the puncture mask data in the decompressed puncture mask being used to delete particular bits from a data sequence." Abe fails to teach or suggest such a memory for the reasons described above with respect to claim 27. Accordingly, claim 34 is now in condition for allowance.

Claims 28-31 and 35-42 are also in condition for allowance because they depend on an allowable base claim, and for the additional limitations contained therein.

Claims 32, 33, and 45 are objected to for being dependent on a rejected base claim, but the Examiner has indicated that they would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.

**Appn No. 09/640,963**  
**Amdt date April 11, 2005**  
**Reply to Office action of January 10, 2005**

In view of the above amendments and remarks, Applicant respectfully requests an early indication of allowance of all pending claims 1-45.

Respectfully submitted,  
CHRISTIE, PARKER & HALE, LLP

By \_\_\_\_\_  
Josephine E. Chang  
Reg. No. 46,083  
626/795-9900

JEC/lal